Qualification Activities at Qorvo for GaN Space Applications

Gergana Drandova, Ph.D.
Qorvo
gergana.drandova@qorvo.com

The talk will cover reliability studies performed on matured GaN technology including transistors, circuits, and passive components covering the entire range of DCLT and RFOLT, electro-migration, TDDB, resistor reliability, hydrogen poisoning, radiation hardness testing, etc.